

Search Notes

Application/Control No.

10/771,538

Examiner

Jean F. Duverne

Applicant(s)/Patent under
Reexamination

MIDORIKAWA ET AL.

Art Unit

2839

SEARCHED

Class	Subclass	Date	Examiner
439	74	4/10/2005	JFD
	660		
	295		
	284		
	81		
	83		
	637	4/10/2005	JFD

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner